

CALL FOR PAPERS



The IEEE AUTOTESTCON 2005 conference will be held at the Renaissance Orlando Resort at Sea World, the most exciting and luxurious resort on "Sea Harbor Drive", in Orlando, Florida, **September 26-29, 2005**. The Technical Program for AUTOTESTCON 2005 will be determined by the interests of those participants who submit for publication and those who organize a technical session, on an appropriate topic dealing with SYSTEM READINESS, in general, and Automatic Test technology, in particular.

IMPORTANT ASPECTS OF SYSTEM READINESS

Verification Diagnostics Logistics Management Instrumentation

The Technical Program committee is particularly interested in developing one or more technical sessions that explore "**Defining the next generation of challenges in Automatic Test**" and address current thought relative to topics such as:

Advances in ATE & TPSs, Software Tools, AI in Test, IT for ATS, Embedded Sensors & Instruments, Integrated Diagnostics & Prognostics, Closed-Loop Diagnostics, BIT/BITE Innovations, Standardization, TPS Transportability, Open Architecture, Logistics and Management, Reusable Software, New Military Requirements/impact, Sustainment Strategies, Performance Based Logistics, Modeling and Simulation, Commercial Systems, Autonomic Logistics, System Health Monitoring, Self-Diagnosing & Self-Healing Systems, Wireless Applications, and Security Challenges

Abstracts for Technical Papers should be one page in length and highlight the main features of the proposed **and previously unpublished** paper dealing with one or more of the important aspects of SYSTEMS READINESS listed above. Session Proposals should include proposed papers/presentations and speakers. The closing date for receipt of Session Proposals and Abstracts for Technical Papers is **March 3, 2005**. Abstracts for Technical Papers may be submitted in hard copy, or in electronic form (Microsoft Word 2000). Abstracts for Technical Papers and Session Proposals must include a point of contact, or author names, organizational affiliation, mailing address, phone/fax numbers, and e-mail address (if applicable). A copyright release will be required at the time of submission for each Technical Paper selected for inclusion in the AUTOTESTCON 2005 Technical Program. All AUTOTESTCON 2005 participants, including authors, presenters, session chairs, and exhibitors must register for the conference. Registration information will be on the AUTOTESTCON 2005 web site at www.autotestcon.com

Abstracts or Session Proposals should be submitted to:

Steve Fairbanks, Technical Program Chairman
Teradyne, Inc.
143 Holden Street
Worcester, MA 01606
(781) 890-2080 (Voice), (978) 370-1440 (Fax)

For other information contact:

Steve Karlovic, General Chairman
Lockheed Martin
12506 Lake Underhill Road, MP 200
Orlando, FL 32825-5002
(407) 306-2351(Voice), (407) 306-2641(Fax)